

## N-Channel 60V MOSFET

### E060N5P4HL1

$V_{DS}$ (V)	$R_{DS(on),max}$ (m $\Omega$ )	$I_D$ (A)
60V	5.4@ $V_{GS} = 10V$	110

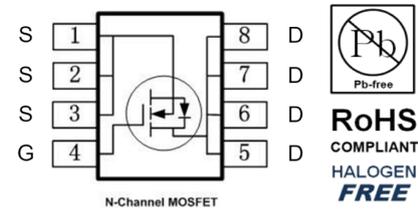
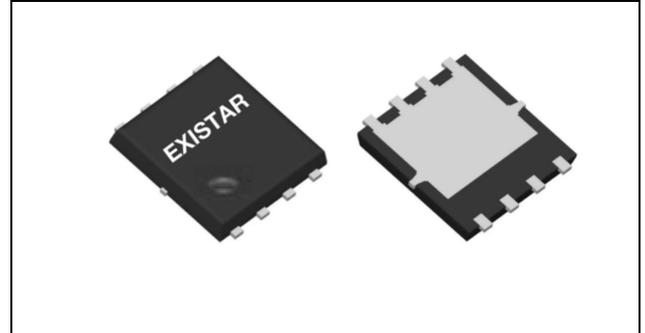
### Features

- Low  $R_{DS(on)}$  trench technology
- Low thermal impedance
- Fast switching speed
- 100% avalanche tested

### Applications

- DC/DC conversion
- Power switch
- PD charger
- Moto driver

### PDFN5X6



### Package And Ordering Information

Ordering code	Package	Marking
E060N5P4HL1	PDFN5X6	E060N5P4HL1

### Ordering Information

Package	Units/ Reel	Reels/ Inner Box	Units/ Inner Box
PDFN5X6	5000	1	5000

**Key Performance Parameters**

Parameter	Value	Unit
VDS, min @ Tj(max)	60	V
ID, pulse	320	A
RDS(ON), max @ VGS=10V	5.4	mΩ
Qg	30	nC

**Absolute Maximum Ratings at Tj=25°C Unless Otherwise Noted**

Parameter	Symbol	Limit	Unit
Drain-source voltage	V <sub>DS</sub>	60	V
Gate-source voltage	V <sub>GS</sub>	±20	
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25°C	110
		T <sub>C</sub> =100°C	-
Pulsed drain current	I <sub>D,pulse</sub>	320	A
Avalanche energy, single pulse	E <sub>AS</sub>	66	mJ
Power dissipation	P <sub>D</sub>	T <sub>C</sub> =25°C	87
		T <sub>A</sub> =25°C	-
Operating junction and storage temperature range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C

**Thermal Characteristics**

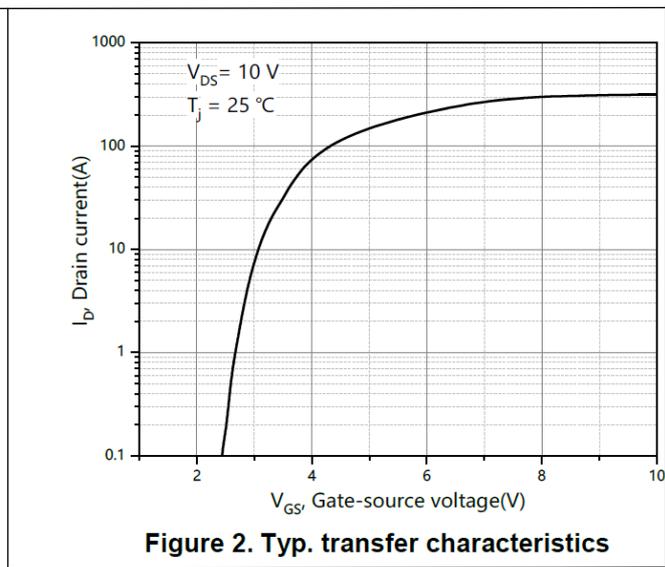
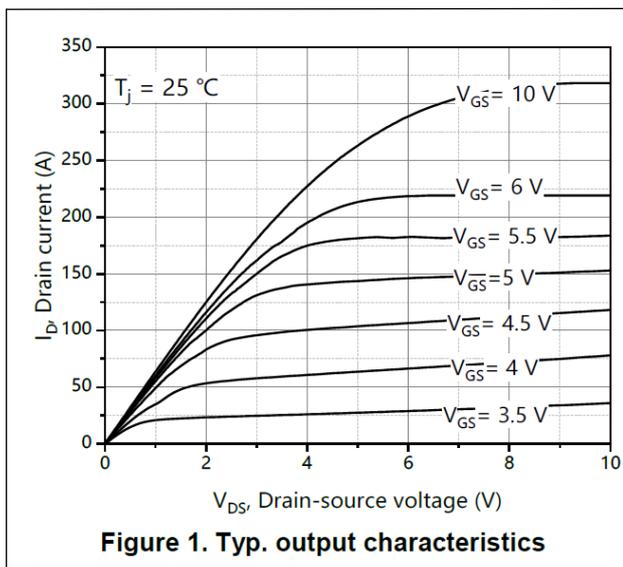
Parameter	Symbol	Max.	Unit
Thermal resistance, junction-to-case	R <sub>θJC</sub>	1.44	°C/W
Thermal resistance, junction-to-ambient	R <sub>θJA</sub>	62	

**Electrical Characteristics at Tj=25°C unless otherwise specified**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test conditions
<b>Static</b>						
Drain to source breakdown voltage	V <sub>(BR)DSS</sub>	60			V	V <sub>GS</sub> = 0, I <sub>D</sub> = 250 μA
Gate-source threshold voltage	V <sub>GS(th)</sub>	1.0		2.5	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA
Gate-body leakage	I <sub>GSS</sub>			±100	nA	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±20 V
Zero gate voltage drain current	I <sub>DSS</sub>			1	μA	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V
Drain-source on-resistance	R <sub>DS(on)</sub>		3.8	5.4	mΩ	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A
Drain-source on-resistance	R <sub>DS(on)</sub>		5.0	6.2	mΩ	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 10 A

Forward transconductance	$g_{fs}$	-	S	$V_{DS} = 5\text{ V}, I_D = 20\text{ A}$
Gate resistance	$R_g$	2.8	$\Omega$	$f = 1\text{ MHz}$
<b>Gate Charge</b>				
Total gate charge	$Q_g$	30	nC	$V_{DS} = 50\text{ V}, I_D = 25\text{ A}, V_{GS} = 10\text{ V}$
Gate-source charge	$Q_{gs}$	5.8		
Gate-drain charge	$Q_{gd}$	6.1		
<b>Dynamic</b>				
Turn-on delay time	$t_{d(on)}$	22.9	ns	$V_{DS} = 50\text{ V}, I_D = 25\text{ A}, V_{GS} = 10\text{ V}, R_{GEN} = 2\ \Omega$
Rise time	$t_r$	6.5		
Turn-off delay time	$t_{d(off)}$	45.7		
Fall time	$t_f$	20.4		
Input capacitance	$C_{iss}$	1750	pF	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}, f = 100\text{ kHz}$
Output capacitance	$C_{oss}$	332		
Reverse transfer capacitance	$C_{rss}$	10.6		
<b>Body Diode</b>				
Diode forward voltage	$V_{SD}$	1.3	V	$V_{GS} = 0\text{ V}, I_F = 20\text{ A}$
Reverse recovery time	$t_{rr}$	50.3	ns	$V_R = 50\text{ V}, I_S = 25\text{ A}, di/dt = 100\text{ A}/\mu\text{s}$
Reverse recovery charge	$Q_{rr}$	45.1	nC	

### Electrical Characteristics Diagrams



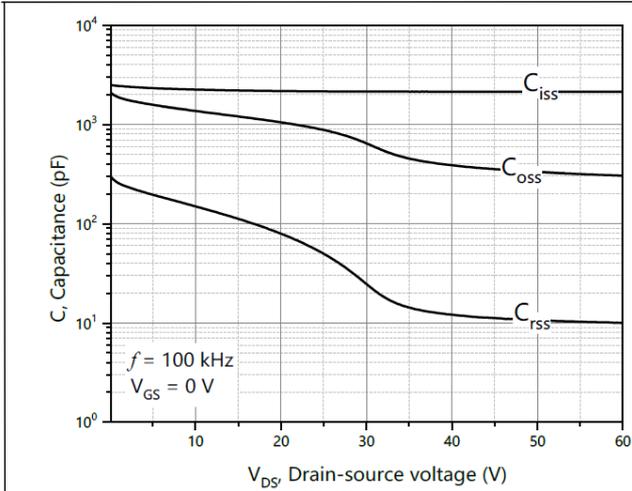


Figure 3. Typ. capacitances

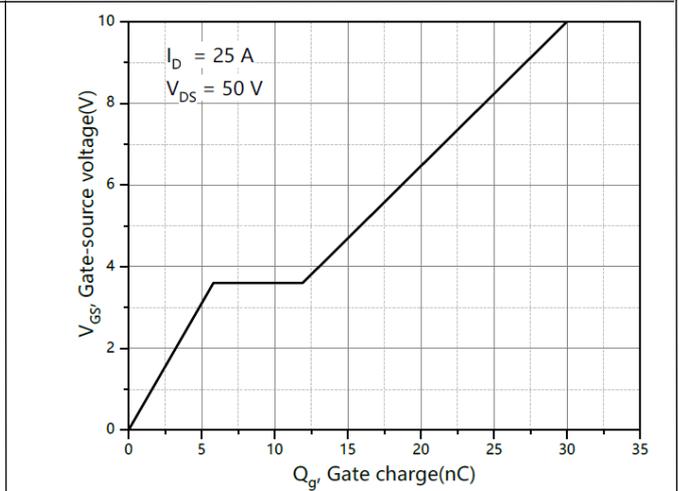


Figure 4. Typ. gate charge

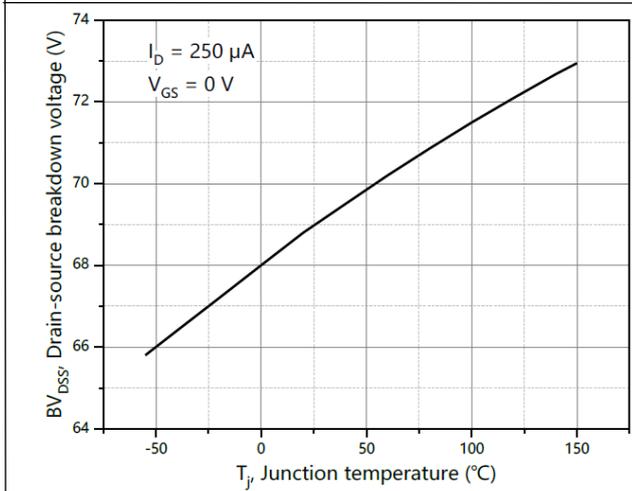


Figure 5. Drain-source breakdown voltage

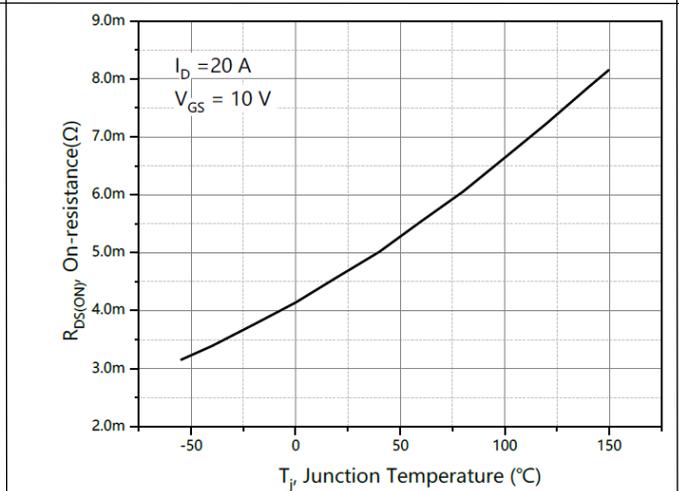


Figure 6. Drain-source on-state resistance

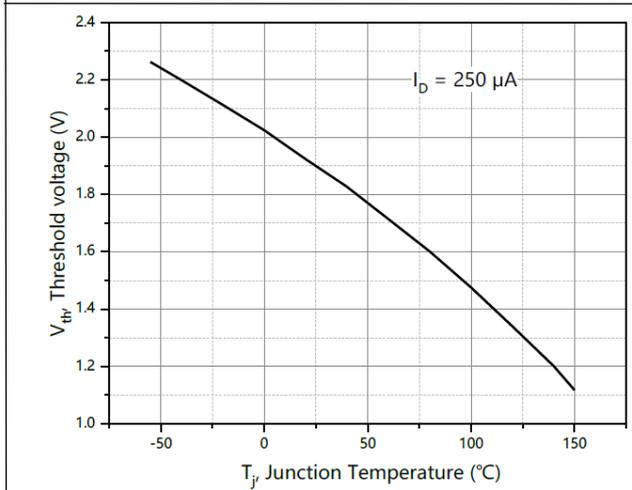


Figure 7. Threshold voltage

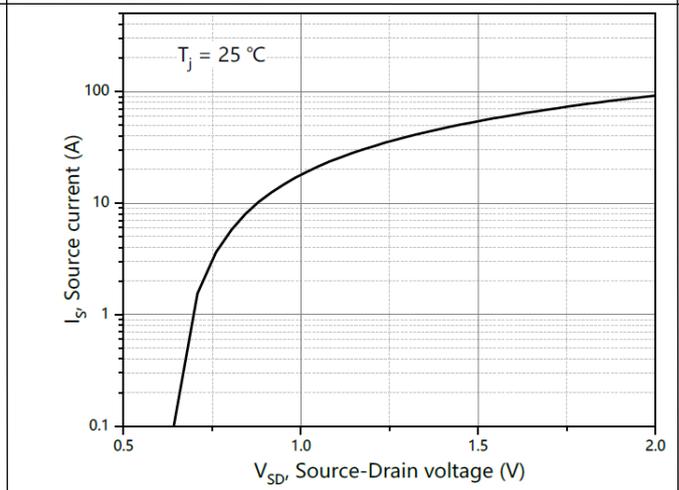


Figure 8. Forward characteristic of body diode

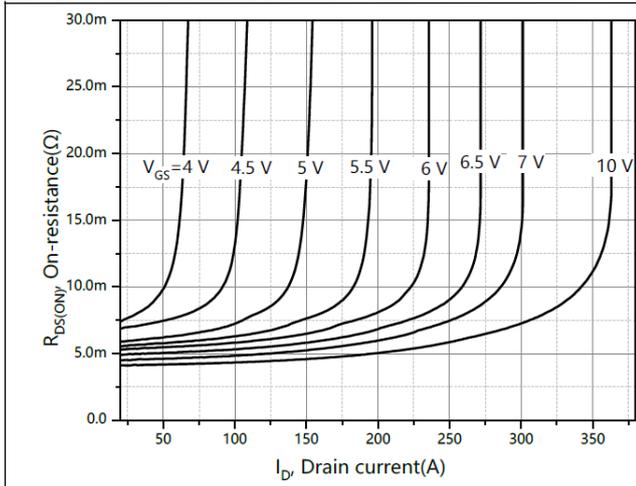


Figure 9. Drain-source on-state resistance

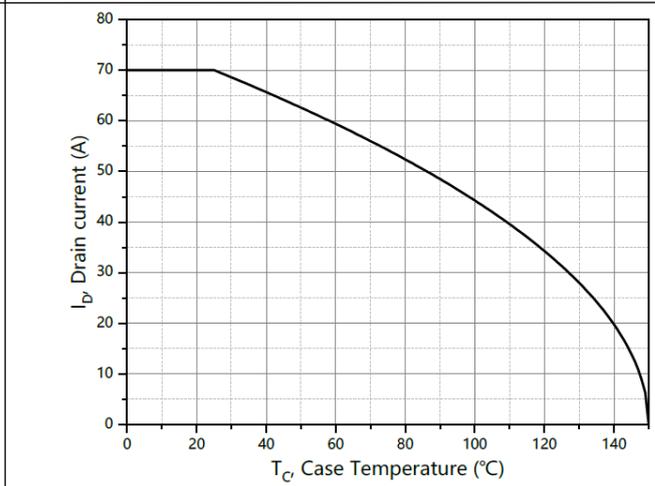


Figure 10. Drain current

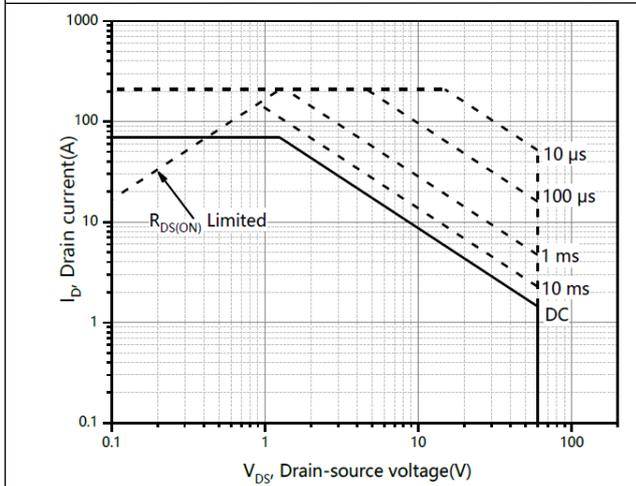


Figure 11. Safe operation area  $T_C=25\text{ }^\circ\text{C}$

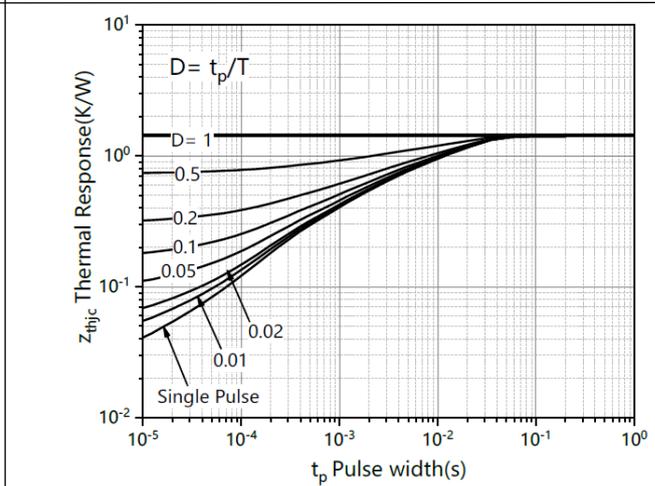


Figure 12. Max. transient thermal impedance



Test circuits and waveforms

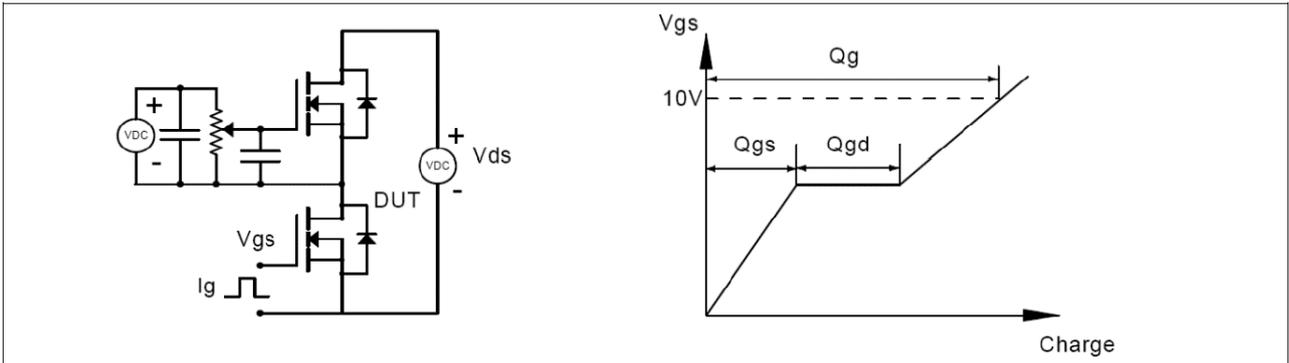


Figure 1. Gate charge test circuit & waveform

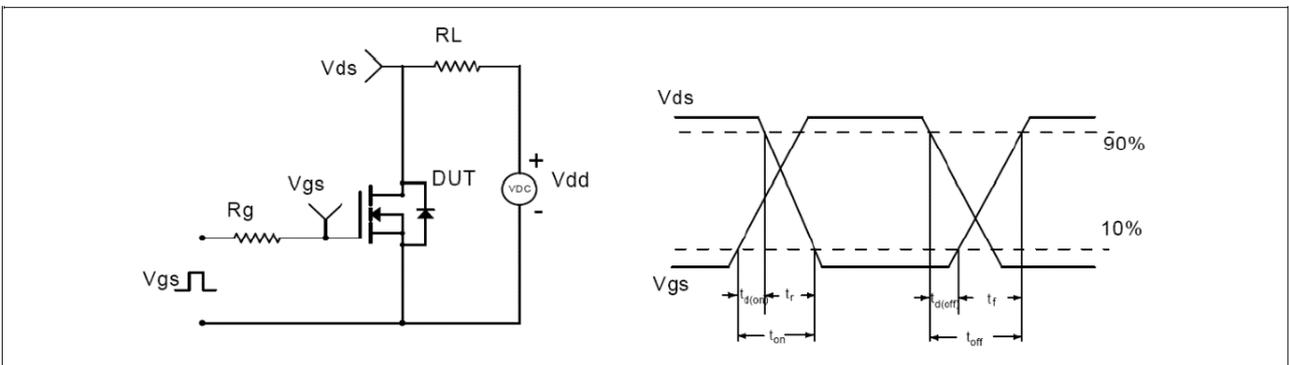


Figure 2. Switching time test circuit & waveforms

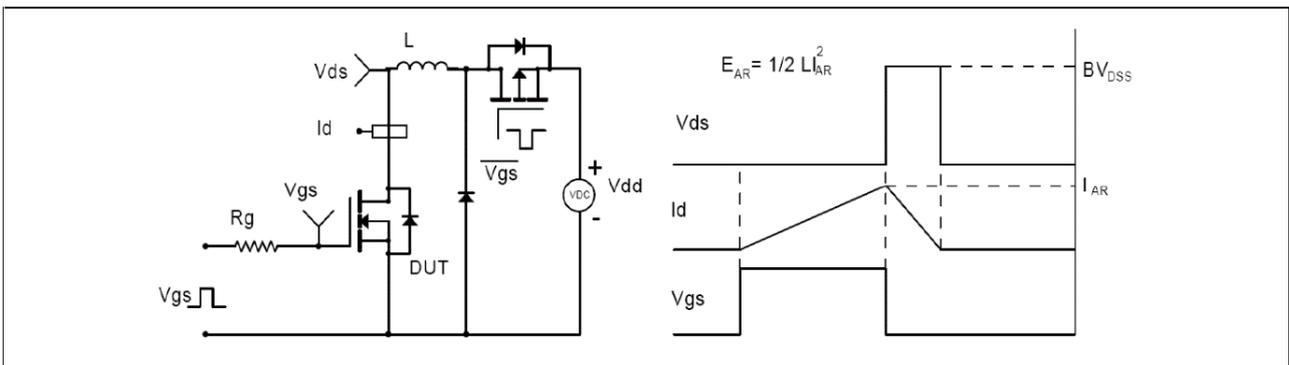


Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

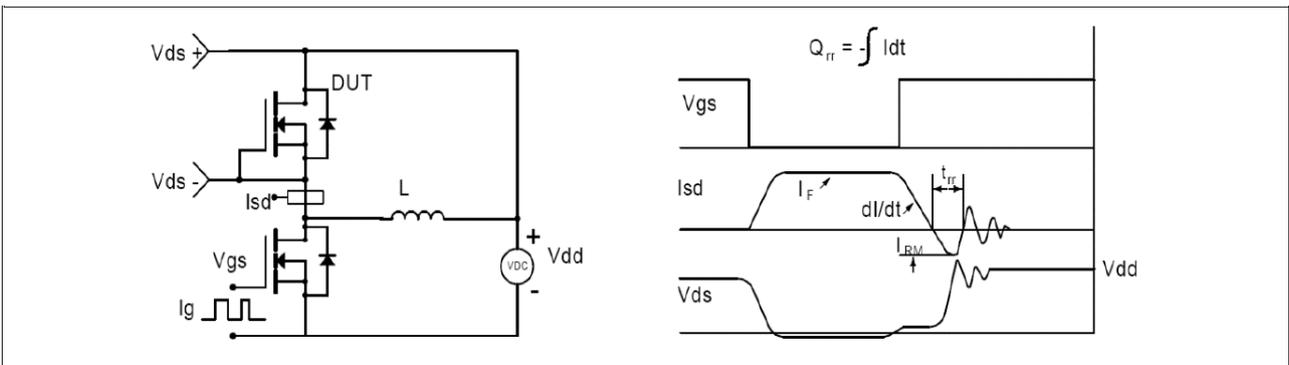


Figure 4. Diode reverse recovery test circuit & waveforms



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